



**INFORMATION CITED BY APPLICANT THAT MAY BE MATERIAL TO THE PROSECUTION OF THE SUBJECT APPLICATION**

Applicant: M. Feldman Attorney Docket No. MEIP122467  
Application No.: 10/814,755 Group Art Unit: 2877  
Filed: March 31, 2004  
Title: IMPROVED WAVELENGTH DETECTOR

**U.S. PATENT DOCUMENTS**

*Examiner Initials	Cite No.	Document No.	Kind Code	Date (mm/dd/yyyy)	Name
PC	U1	4,308,456	A	12/29/1981	Van Der Gaag et al.
PC	U2	5,627,648	A	05/06/1997	Garrett
PC	U3	5,729,347	A	03/17/1998	So
PC	U4	2002/0126288	A1	09/12/2002	Friberg et al.

**FOREIGN PATENT DOCUMENTS**

*Examiner Initials	Cite No.	Document No.	Kind Code	Publication Date (mm/dd/yyyy)	Country	English Provided	Abstract Provided	Translation Provided
None								

**OTHER INFORMATION**  
**(Including Author, Title, Date, Pertinent Pages, Etc.)**

*Examiner Initials	Cite No.
None	

Examiner	Date Considered
/Patrick Connolly/	(08/29/2006)

\*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

SIL:vas